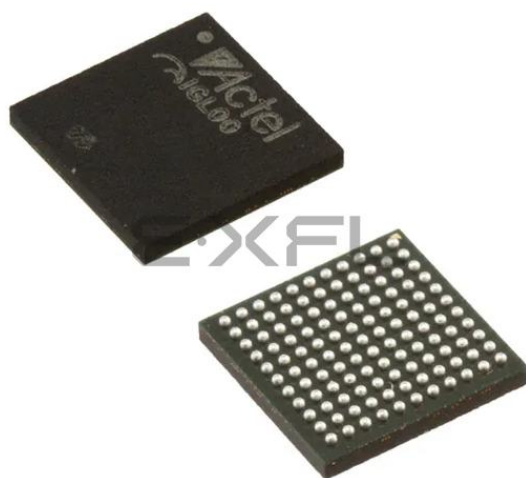




Welcome to [E-XFL.COM](#)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	1536
Total RAM Bits	18432
Number of I/O	96
Number of Gates	60000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	121-VFBGA, CSBGA
Supplier Device Package	121-CSP (6x6)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/agl060v2-cs121i

IGLOO Device Family Overview

General Description	1-1
---------------------------	-----

IGLOO DC and Switching Characteristics

General Specifications	2-1
Calculating Power Dissipation	2-7
Power Calculation Methodology	2-17
User I/O Characteristics	2-20
VersaTile Characteristics	2-100
Global Resource Characteristics	2-106
Clock Conditioning Circuits	2-115
Embedded SRAM and FIFO Characteristics	2-118
Embedded FlashROM Characteristics	2-132
JTAG 1532 Characteristics	2-133

Pin Descriptions

Supply Pins	3-1
User Pins	3-2
JTAG Pins	3-4
Special Function Pins	3-5
Packaging	3-5
Related Documents	3-5

Package Pin Assignments

UC81	4-1
CS81	4-3
CS121	4-6
CS196	4-9
CS281	4-16
QN48	4-23
QN68	4-25
QN132	4-28
VQ100	4-37
FG144	4-42
FG256	4-53
FG484	4-63

Datasheet Information

List of Changes	5-1
Datasheet Categories	5-13
Safety Critical, Life Support, and High-Reliability Applications Policy	5-13

2 – IGLOO DC and Switching Characteristics

General Specifications

Operating Conditions

Stresses beyond those listed in [Table 2-1](#) may cause permanent damage to the device.

Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Absolute Maximum Ratings are stress ratings only; functional operation of the device at these or any other conditions beyond those listed under the Recommended Operating Conditions specified in [Table 2-2 on page 2-2](#) is not implied.

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits ¹	Units
VCC	DC core supply voltage	–0.3 to 1.65	V
VJTAG	JTAG DC voltage	–0.3 to 3.75	V
VPUMP	Programming voltage	–0.3 to 3.75	V
VCCPLL	Analog power supply (PLL)	–0.3 to 1.65	V
VCCI and VMV ²	DC I/O buffer supply voltage	–0.3 to 3.75	V
VI	I/O input voltage	–0.3 V to 3.6 V (when I/O hot insertion mode is enabled) –0.3 V to (VCCI + 1 V) or 3.6 V, whichever voltage is lower (when I/O hot-insertion mode is disabled)	V
T _{STG} ³	Storage Temperature	–65 to +150	°C
T _J ³	Junction Temperature	+125	°C

Notes:

1. The device should be operated within the limits specified by the datasheet. During transitions, the input signal may undershoot or overshoot according to the limits shown in [Table 2-4 on page 2-3](#).
2. VMV pins must be connected to the corresponding VCCI pins. See the "Pin Descriptions" chapter of the [IGLOO FPGA Fabric User Guide](#) for further information.
3. For flash programming and retention, maximum limits refer to [Table 2-3 on page 2-3](#), and for recommended operating limits, refer to [Table 2-2 on page 2-2](#).

Table 2-15 • Summary of I/O Input Buffer Power (per pin) – Default I/O Software Settings
Applicable to Standard I/O Banks

	VCCI (V)	Static Power PDC6 (mW) ¹	Dynamic Power PAC9 (μW/MHz) ²
Single-Ended			
3.3 V LVTTTL / 3.3 V LVCMOS	3.3	–	17.24
3.3 V LVCMOS Wide Range ³	3.3	–	17.24
2.5 V LVCMOS	2.5	–	5.64
1.8 V LVCMOS	1.8	–	2.63
1.5 V LVCMOS (JESD8-11)	1.5	–	1.97
1.2 V LVCMOS ⁴	1.2	–	0.57
1.2 V LVCMOS Wide Range ⁴	1.2	–	0.57

Notes:

1. PDC6 is the static power (where applicable) measured on VCCI.
2. PAC9 is the total dynamic power measured on VCCI.
3. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.
4. Applicable for IGLOO V2 devices only.

Table 2-16 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings¹
Applicable to Advanced I/O Banks

	C _{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μW/MHz) ³
Single-Ended				
3.3 V LVTTTL / 3.3 V LVCMOS	5	3.3	–	136.95
3.3 V LVCMOS Wide Range ⁴	5	3.3	–	136.95
2.5 V LVCMOS	5	2.5	–	76.84
1.8 V LVCMOS	5	1.8	–	49.31
1.5 V LVCMOS (JESD8-11)	5	1.5	–	33.36
1.2 V LVCMOS ⁵	5	1.2	–	16.24
1.2 V LVCMOS Wide Range ⁵	5	1.2	–	16.24
3.3 V PCI	10	3.3	–	194.05
3.3 V PCI-X	10	3.3	–	194.05
Differential				
LVDS	–	2.5	7.74	156.22
LVPECL	–	3.3	19.54	339.35

Notes:

1. Dynamic power consumption is given for standard load and software default drive strength and output slew.
2. PDC7 is the static power (where applicable) measured on VCCI.
3. PAC10 is the total dynamic power measured on VCCI.
4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.
5. Applicable for IGLOO V2 devices only.

User I/O Characteristics

Timing Model

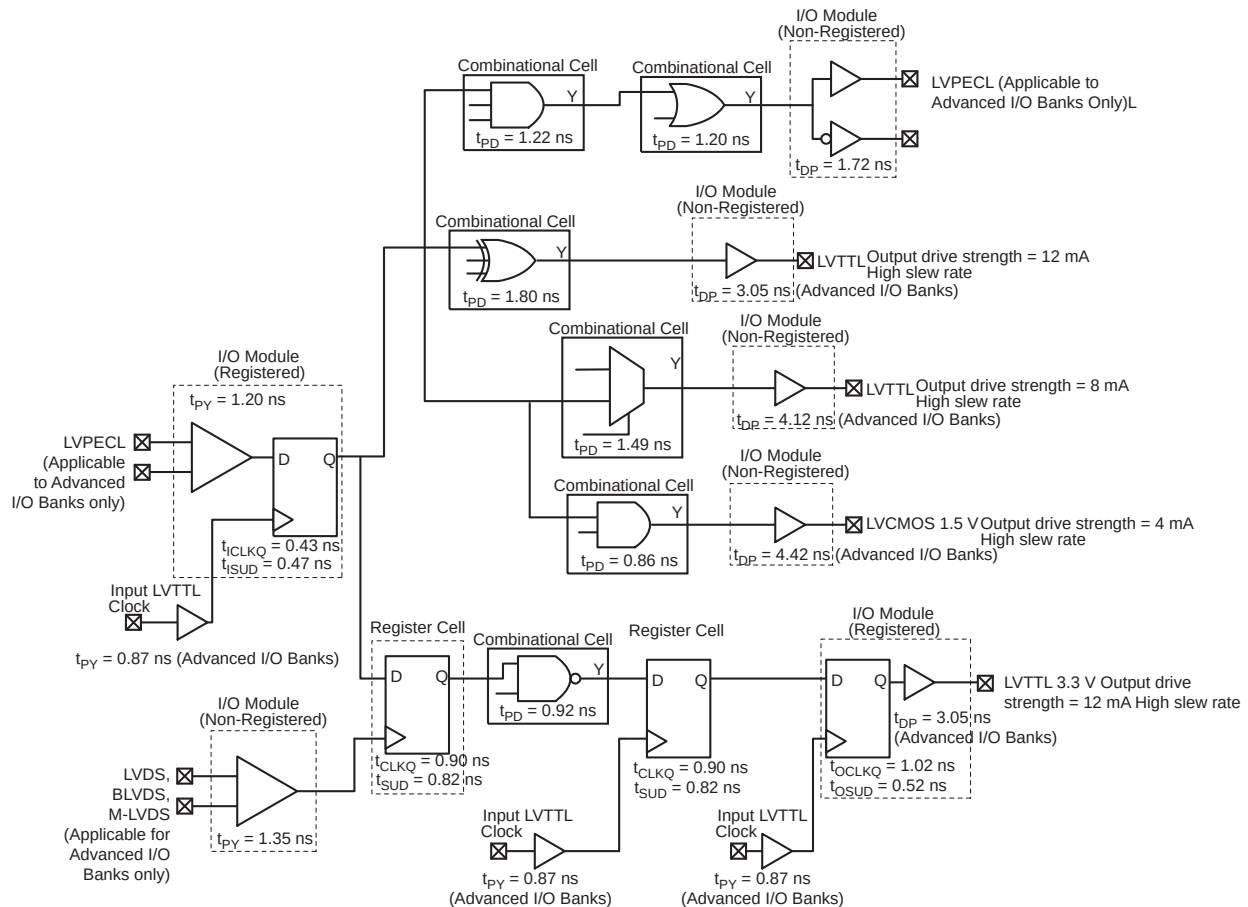


Figure 2-3 • Timing Model

Operating Conditions: Std. Speed, Commercial Temperature Range ($T_J = 70^\circ\text{C}$), Worst-Case $V_{CC} = 1.425$ V, for DC 1.5 V Core Voltage, Applicable to V2 and V5 Devices

Table 2-104 • 1.8 V LVC MOS High Slew – Applies to 1.5 V DC Core VoltageCommercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.7 V

Applicable to Standard Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	Std.	2.62	0.18	0.98	0.66	2.67	2.59	1.67	1.29	2.62	ns
4 mA	Std.	2.18	0.18	0.98	0.66	2.22	1.93	1.97	2.06	2.18	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-7](#) for derating values.

1.2 V DC Core Voltage**Table 2-105 • 1.8 V LVC MOS Low Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.7 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	6.97	0.26	1.11	1.10	7.08	6.48	2.87	2.29	12.87	12.27	ns
4 mA	Std.	1.55	5.91	0.26	1.11	1.10	6.01	5.57	3.21	3.14	11.79	11.36	ns
6 mA	Std.	1.55	5.16	0.26	1.11	1.10	5.24	4.95	3.45	3.55	11.03	10.74	ns
8 mA	Std.	1.55	4.90	0.26	1.11	1.10	4.98	4.81	3.50	3.66	10.77	10.60	ns
12 mA	Std.	1.55	4.83	0.26	1.11	1.10	4.90	4.83	3.58	4.08	10.68	10.61	ns
16 mA	Std.	1.55	4.83	0.26	1.11	1.10	4.90	4.83	3.58	4.08	10.68	10.61	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-7](#) for derating values.**Table 2-106 • 1.8 V LVC MOS High Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.7 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	3.73	0.26	1.11	1.10	3.71	3.73	2.86	2.34	9.49	9.51	ns
4 mA	Std.	1.55	3.12	0.26	1.11	1.10	3.16	2.97	3.21	3.22	8.95	8.75	ns
6 mA	Std.	1.55	2.79	0.26	1.11	1.10	2.83	2.59	3.45	3.65	8.62	8.38	ns
8 mA	Std.	1.55	2.73	0.26	1.11	1.10	2.77	2.52	3.50	3.75	8.56	8.30	ns
12 mA	Std.	1.55	2.72	0.26	1.11	1.10	2.76	2.43	3.58	4.19	8.55	8.22	ns
16 mA	Std.	1.55	2.72	0.26	1.11	1.10	2.76	2.43	3.58	4.19	8.55	8.22	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-7](#) for derating values.

Table 2-119 • 1.5 V LVC MOS Low Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.4 V

Applicable to Standard Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	Std.	0.97	5.88	0.18	1.14	0.66	6.00	5.45	2.00	1.94	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-7](#) for derating values.

Table 2-120 • 1.5 V LVC MOS High Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.4 V

Applicable to Standard Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	Std.	0.97	2.51	0.18	1.14	0.66	2.56	2.21	1.99	2.03	ns

Notes:

- Software default selection highlighted in gray.
- For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-7](#) for derating values.

1.2 V DC Core Voltage

Table 2-121 • 1.5 V LVC MOS Low Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	7.17	0.26	1.27	1.10	7.29	6.60	3.33	3.03	13.07	12.39	ns
4 mA	Std.	1.55	6.27	0.26	1.27	1.10	6.37	5.86	3.61	3.51	12.16	11.64	ns
6 mA	Std.	1.55	5.94	0.26	1.27	1.10	6.04	5.70	3.67	3.64	11.82	11.48	ns
8 mA	Std.	1.55	5.86	0.26	1.27	1.10	5.96	5.71	2.83	4.11	11.74	11.50	ns
12 mA	Std.	1.55	5.86	0.26	1.27	1.10	5.96	5.71	2.83	4.11	11.74	11.50	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-7](#) for derating values.

Table 2-122 • 1.5 V LVC MOS High Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	3.44	0.26	1.27	1.10	3.49	3.35	3.32	3.12	9.28	9.14	ns
4 mA	Std.	1.55	3.06	0.26	1.27	1.10	3.10	2.89	3.60	3.61	8.89	8.67	ns
6 mA	Std.	1.55	2.98	0.26	1.27	1.10	3.02	2.80	3.66	3.74	8.81	8.58	ns
8 mA	Std.	1.55	2.96	0.26	1.27	1.10	3.00	2.70	3.75	4.23	8.78	8.48	ns
12 mA	Std.	1.55	2.96	0.26	1.27	1.10	3.00	2.70	3.75	4.23	8.78	8.48	ns

Notes:

- Software default selection highlighted in gray.
- For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-7](#) for derating values.

B-LVDS/M-LVDS

Bus LVDS (B-LVDS) and Multipoint LVDS (M-LVDS) specifications extend the existing LVDS standard to high-performance multipoint bus applications. Multidrop and multipoint bus configurations may contain any combination of drivers, receivers, and transceivers. Microsemi LVDS drivers provide the higher drive current required by B-LVDS and M-LVDS to accommodate the loading. The drivers require series terminations for better signal quality and to control voltage swing. Termination is also required at both ends of the bus since the driver can be located anywhere on the bus. These configurations can be implemented using the TRIBUF_LVDS and BIBUF_LVDS macros along with appropriate terminations. Multipoint designs using Microsemi LVDS macros can achieve up to 200 MHz with a maximum of 20 loads. A sample application is given in Figure 2-14. The input and output buffer delays are available in the LVDS section in Table 2-149 on page 2-81 and Table 2-150 on page 2-81.

Example: For a bus consisting of 20 equidistant loads, the following terminations provide the required differential voltage, in worst-case Industrial operating conditions, at the farthest receiver: $R_S = 60 \Omega$ and $R_T = 70 \Omega$, given $Z_0 = 50 \Omega$ (2") and $Z_{stub} = 50 \Omega$ (~1.5").

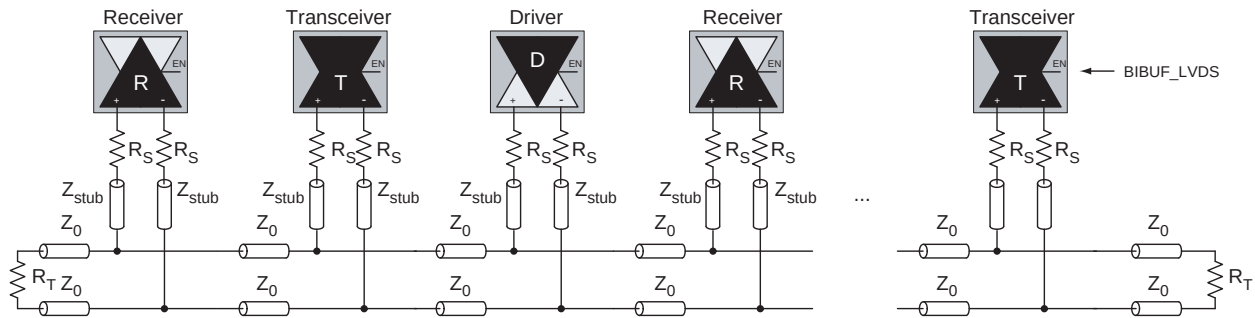


Figure 2-14 • B-LVDS/M-LVDS Multipoint Application Using LVDS I/O Buffers

LVPECL

Low-Voltage Positive Emitter-Coupled Logic (LVPECL) is another differential I/O standard. It requires that one data bit be carried through two signal lines. Like LVDS, two pins are needed. It also requires external resistor termination.

The full implementation of the LVDS transmitter and receiver is shown in an example in Figure 2-15. The building blocks of the LVPECL transmitter-receiver are one transmitter macro, one receiver macro, three board resistors at the transmitter end, and one resistor at the receiver end. The values for the three driver resistors are different from those used in the LVDS implementation because the output standard specifications are different.

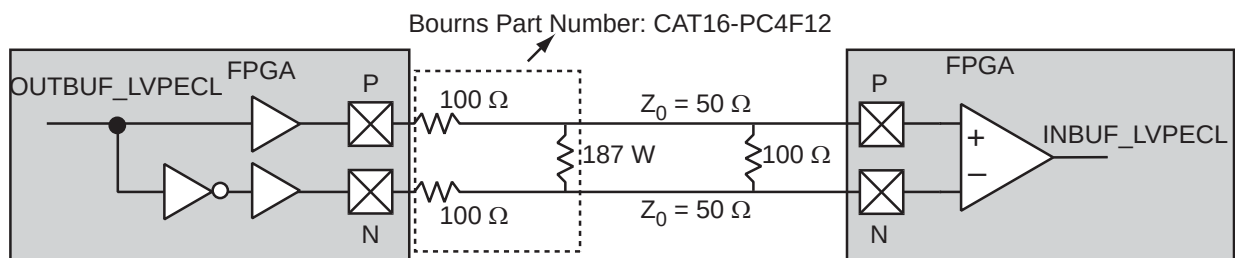


Figure 2-15 • LVPECL Circuit Diagram and Board-Level Implementation

Global Resource Characteristics

AGL250 Clock Tree Topology

Clock delays are device-specific. Figure 2-29 is an example of a global tree used for clock routing. The global tree presented in Figure 2-29 is driven by a CCC located on the west side of the AGL250 device. It is used to drive all D-flip-flops in the device.

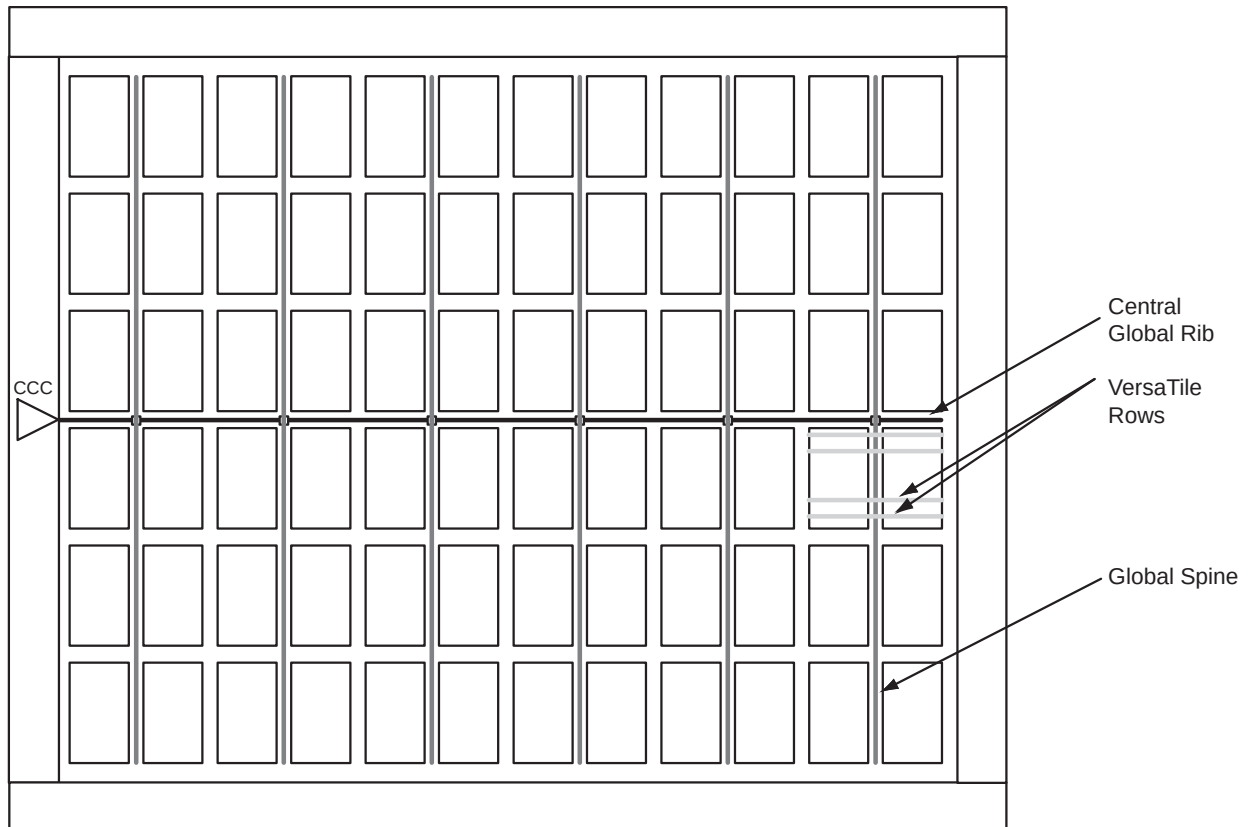


Figure 2-29 • Example of Global Tree Use in an AGL250 Device for Clock Routing

Table 2-187 • AGL600 Global Resource
Commercial-Case Conditions: $T_J = 70^{\circ}\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.		Units
		Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	2.22	2.67	ns
t_{RCKH}	Input High Delay for Global Clock	2.32	2.93	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	1.40		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	1.65		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.61	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-7](#) for derating values.

Table 2-188 • AGL1000 Global Resource
Commercial-Case Conditions: $T_J = 70^{\circ}\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.		Units
		Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	2.31	2.76	ns
t_{RCKH}	Input High Delay for Global Clock	2.42	3.03	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	1.40		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	1.65		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.61	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-7](#) for derating values.

Embedded SRAM and FIFO Characteristics

SRAM

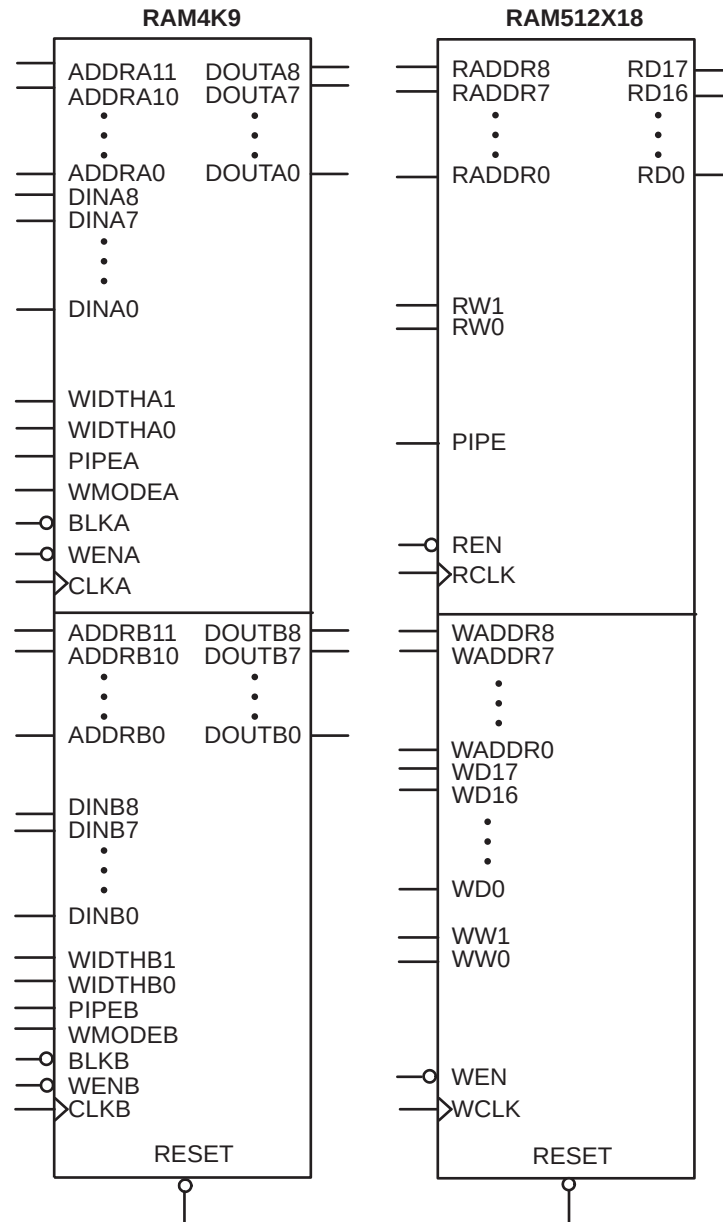


Figure 2-31 • RAM Models

1.2 V DC Core Voltage

Table 2-196 • FIFO
Worst Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.	Units
t_{ENS}	REN, WEN Setup Time	4.13	ns
t_{ENH}	REN, WEN Hold Time	0.31	ns
t_{BKS}	BLK Setup Time	0.47	ns
t_{BKH}	BLK Hold Time	0.00	ns
t_{DS}	Input Data (WD) Setup Time	1.56	ns
t_{DH}	Input Data (WD) Hold Time	0.49	ns
t_{CKQ1}	Clock High to New Data Valid on RD (flow-through)	6.80	ns
t_{CKQ2}	Clock High to New Data Valid on RD (pipelined)	3.62	ns
t_{RCKEF}	RCLK High to Empty Flag Valid	7.23	ns
t_{WCKFF}	WCLK High to Full Flag Valid	6.85	ns
t_{CKAF}	Clock High to Almost Empty/Full Flag Valid	26.61	ns
t_{RSTFG}	RESET Low to Empty/Full Flag Valid	7.12	ns
t_{RSTAF}	RESET Low to Almost Empty/Full Flag Valid	26.33	ns
t_{RSTBQ}	RESET Low to Data Out Low on RD (flow-through)	4.09	ns
	RESET Low to Data Out Low on RD (pipelined)	4.09	ns
$t_{REMRSTB}$	RESET Removal	1.23	ns
$t_{RECRSTB}$	RESET Recovery	6.58	ns
$t_{MPWRSTB}$	RESET Minimum Pulse Width	1.18	ns
t_{CYC}	Clock Cycle Time	10.90	ns
F_{MAX}	Maximum Frequency for FIFO	92	MHz

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-7](#) for derating values.

JTAG 1532 Characteristics

JTAG timing delays do not include JTAG I/Os. To obtain complete JTAG timing, add I/O buffer delays to the corresponding standard selected; refer to the I/O timing characteristics in the "User I/O Characteristics" section on page 2-20 for more details.

Timing Characteristics

Table 2-199 • JTAG 1532

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V

Parameter	Description	Std.	Units
t_{DISU}	Test Data Input Setup Time	1.00	ns
t_{DIHD}	Test Data Input Hold Time	2.00	ns
t_{TMSSU}	Test Mode Select Setup Time	1.00	ns
t_{TMDHD}	Test Mode Select Hold Time	2.00	ns
t_{TCK2Q}	Clock to Q (data out)	8.00	ns
t_{RSTB2Q}	Reset to Q (data out)	25.00	ns
F_{TCKMAX}	TCK Maximum Frequency	15	MHz
t_{TRSTREM}	ResetB Removal Time	0.58	ns
t_{TRSTREC}	ResetB Recovery Time	0.00	ns
t_{TRSTMPW}	ResetB Minimum Pulse	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-200 • JTAG 1532

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V

Parameter	Description	Std.	Units
t_{DISU}	Test Data Input Setup Time	1.50	ns
t_{DIHD}	Test Data Input Hold Time	3.00	ns
t_{TMSSU}	Test Mode Select Setup Time	1.50	ns
t_{TMDHD}	Test Mode Select Hold Time	3.00	ns
t_{TCK2Q}	Clock to Q (data out)	11.00	ns
t_{RSTB2Q}	Reset to Q (data out)	30.00	ns
F_{TCKMAX}	TCK Maximum Frequency	9.00	MHz
t_{TRSTREM}	ResetB Removal Time	1.18	ns
t_{TRSTREC}	ResetB Recovery Time	0.00	ns
t_{TRSTMPW}	ResetB Minimum Pulse	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Note that to operate at all VJTAG voltages, 500 Ω to 1 k Ω will satisfy the requirements.

Special Function Pins

NC

No Connect

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

DC

Do Not Connect

This pin should not be connected to any signals on the PCB. These pins should be left unconnected.

Packaging

Semiconductor technology is constantly shrinking in size while growing in capability and functional integration. To enable next-generation silicon technologies, semiconductor packages have also evolved to provide improved performance and flexibility.

Microsemi consistently delivers packages that provide the necessary mechanical and environmental protection to ensure consistent reliability and performance. Microsemi IC packaging technology efficiently supports high-density FPGAs with large-pin-count Ball Grid Arrays (BGAs), but is also flexible enough to accommodate stringent form factor requirements for Chip Scale Packaging (CSP). In addition, Microsemi offers a variety of packages designed to meet your most demanding application and economic requirements for today's embedded and mobile systems.

Related Documents

User Guides

IGLOO FPGA Fabric User Guide

http://www.microsemi.com/soc/documents/IGLOO_UG.pdf

Packaging Documents

The following documents provide packaging information and device selection for low power flash devices.

Product Catalog

http://www.microsemi.com/soc/documents/ProdCat_PIB.pdf

Lists devices currently recommended for new designs and the packages available for each member of the family. Use this document or the datasheet tables to determine the best package for your design, and which package drawing to use.

Package Mechanical Drawings

<http://www.microsemi.com/soc/documents/PckgMechDrwns.pdf>

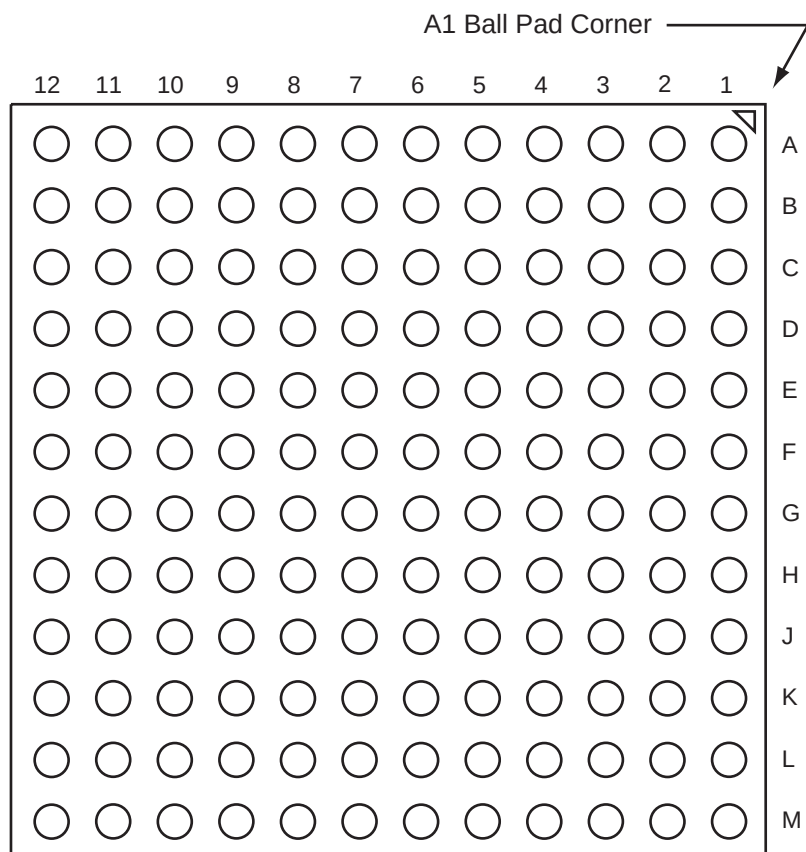
This document contains the package mechanical drawings for all packages currently or previously supplied by Microsemi. Use the bookmarks to navigate to the package mechanical drawings.

Additional packaging materials are available on the Microsemi SoC Products Group website at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>.

CS281	
Pin Number	AGL1000 Function
R15	IO122RSB2
R16	GDA1/IO113PPB1
R18	GDB0/IO112NPB1
R19	GDC0/IO111NPB1
T1	IO197PPB3
T2	GEC0/IO190NPB3
T4	GEB0/IO189NPB3
T5	IO181RSB2
T6	IO172RSB2
T7	IO171RSB2
T8	IO156RSB2
T9	IO159RSB2
T10	GND
T11	IO139RSB2
T12	IO138RSB2
T13	IO129RSB2
T14	IO123RSB2
T15	GDC2/IO116RSB2
T16	TMS
T18	VJTAG
T19	GDB1/IO112PPB1
U1	IO193PDB3
U2	GEA1/IO188PPB3
U6	IO167RSB2
U14	IO128RSB2
U18	TRST
U19	GDA0/IO113NPB1
V1	IO193NDB3
V2	VCCIB3
V3	GEC2/IO185RSB2
V4	IO182RSB2
V5	IO175RSB2
V6	GND
V7	IO161RSB2
V8	IO143RSB2
V9	IO146RSB2

CS281	
Pin Number	AGL1000 Function
V10	IO145RSB2
V11	IO144RSB2
V12	IO134RSB2
V13	IO133RSB2
V14	GND
V15	IO119RSB2
V16	GDA2/IO114RSB2
V17	TDI
V18	VCCIB2
V19	TDO
W1	GND
W2	FF/GEB2/IO186RSB2
W3	IO183RSB2
W4	IO176RSB2
W5	IO170RSB2
W6	IO162RSB2
W7	IO157RSB2
W8	IO152RSB2
W9	IO149RSB2
W10	VCCIB2
W11	IO140RSB2
W12	IO135RSB2
W13	IO130RSB2
W14	IO125RSB2
W15	IO120RSB2
W16	IO118RSB2
W17	GDB2/IO115RSB2
W18	TCK
W19	GND

FG144



Note: This is the bottom view of the package.

Note

For more information on package drawings, see [PD3068: Package Mechanical Drawings](#).

FG484	
Pin Number	AGL400 Function
C21	NC
C22	VCCIB1
D1	NC
D2	NC
D3	NC
D4	GND
D5	GAA0/IO00RSB0
D6	GAA1/IO01RSB0
D7	GAB0/IO02RSB0
D8	IO16RSB0
D9	IO17RSB0
D10	IO22RSB0
D11	IO28RSB0
D12	IO34RSB0
D13	IO37RSB0
D14	IO41RSB0
D15	IO43RSB0
D16	GBB1/IO57RSB0
D17	GBA0/IO58RSB0
D18	GBA1/IO59RSB0
D19	GND
D20	NC
D21	NC
D22	NC
E1	NC
E2	NC
E3	GND
E4	GAB2/IO154UDB3
E5	GAA2/IO155UDB3
E6	IO12RSB0
E7	GAB1/IO03RSB0
E8	IO13RSB0
E9	IO14RSB0
E10	IO21RSB0
E11	IO27RSB0
E12	IO32RSB0

FG484	
Pin Number	AGL400 Function
H19	IO66PDB1
H20	VCC
H21	NC
H22	NC
J1	NC
J2	NC
J3	NC
J4	IO150NDB3
J5	IO149NPB3
J6	IO09RSB0
J7	IO152UDB3
J8	VCCIB3
J9	GND
J10	VCC
J11	VCC
J12	VCC
J13	VCC
J14	GND
J15	VCCIB1
J16	IO62NDB1
J17	IO49RSB0
J18	IO64PPB1
J19	IO66NDB1
J20	NC
J21	NC
J22	NC
K1	NC
K2	NC
K3	NC
K4	IO148NDB3
K5	IO148PDB3
K6	IO149PPB3
K7	GFC1/IO147PPB3
K8	VCCIB3
K9	VCC
K10	GND

FG484	
Pin Number	AGL600 Function
A1	GND
A2	GND
A3	VCCIB0
A4	NC
A5	NC
A6	IO09RSB0
A7	IO15RSB0
A8	NC
A9	NC
A10	IO22RSB0
A11	IO23RSB0
A12	IO29RSB0
A13	IO35RSB0
A14	NC
A15	NC
A16	IO46RSB0
A17	IO48RSB0
A18	NC
A19	NC
A20	VCCIB0
A21	GND
A22	GND
AA1	GND
AA2	VCCIB3
AA3	NC
AA4	NC
AA5	NC
AA6	IO135RSB2
AA7	IO133RSB2
AA8	NC
AA9	NC
AA10	NC
AA11	NC
AA12	NC
AA13	NC
AA14	NC

FG484	
Pin Number	AGL600 Function
AA15	NC
AA16	IO101RSB2
AA17	NC
AA18	NC
AA19	NC
AA20	NC
AA21	VCCIB1
AA22	GND
AB1	GND
AB2	GND
AB3	VCCIB2
AB4	NC
AB5	NC
AB6	IO130RSB2
AB7	IO128RSB2
AB8	IO122RSB2
AB9	IO116RSB2
AB10	NC
AB11	NC
AB12	IO113RSB2
AB13	IO112RSB2
AB14	NC
AB15	NC
AB16	IO100RSB2
AB17	IO95RSB2
AB18	NC
AB19	NC
AB20	VCCIB2
AB21	GND
AB22	GND
B1	GND
B2	VCCIB3
B3	NC
B4	NC
B5	NC
B6	IO08RSB0

FG484	
Pin Number	AGL600 Function
B7	IO12RSB0
B8	NC
B9	NC
B10	IO17RSB0
B11	NC
B12	NC
B13	IO36RSB0
B14	NC
B15	NC
B16	IO47RSB0
B17	IO49RSB0
B18	NC
B19	NC
B20	NC
B21	VCCIB1
B22	GND
C1	VCCIB3
C2	NC
C3	NC
C4	NC
C5	GND
C6	NC
C7	NC
C8	VCC
C9	VCC
C10	NC
C11	NC
C12	NC
C13	NC
C14	VCC
C15	VCC
C16	NC
C17	NC
C18	GND
C19	NC
C20	NC

FG484	
Pin Number	AGL600 Function
M3	IO158NPB3
M4	GFA2/IO161PPB3
M5	GFA1/IO162PDB3
M6	VCCPLF
M7	IO160NDB3
M8	GFB2/IO160PDB3
M9	VCC
M10	GND
M11	GND
M12	GND
M13	GND
M14	VCC
M15	GCB2/IO73PPB1
M16	GCA1/IO71PPB1
M17	GCC2/IO74PPB1
M18	IO80PPB1
M19	GCA2/IO72PDB1
M20	IO79PPB1
M21	IO78PPB1
M22	NC
N1	IO154NDB3
N2	IO154PDB3
N3	NC
N4	GFC2/IO159PDB3
N5	IO161NPB3
N6	IO156PPB3
N7	IO129RSB2
N8	VCCIB3
N9	VCC
N10	GND
N11	GND
N12	GND
N13	GND
N14	VCC
N15	VCCIB1
N16	IO73NPB1

FG484	
Pin Number	AGL600 Function
V15	IO96RSB2
V16	GDB2/IO90RSB2
V17	TDI
V18	GNDQ
V19	TDO
V20	GND
V21	NC
V22	NC
W1	NC
W2	IO148PDB3
W3	NC
W4	GND
W5	IO137RSB2
W6	FF/GEB2/IO142RSB2
W7	IO134RSB2
W8	IO125RSB2
W9	IO123RSB2
W10	IO118RSB2
W11	IO115RSB2
W12	IO111RSB2
W13	IO106RSB2
W14	IO102RSB2
W15	GDC2/IO91RSB2
W16	IO93RSB2
W17	GDA2/IO89RSB2
W18	TMS
W19	GND
W20	NC
W21	NC
W22	NC
Y1	VCCIB3
Y2	IO148NDB3
Y3	NC
Y4	NC
Y5	GND
Y6	NC